

<b>Notice of References Cited</b>	Application/Control No. 10/648,199	Applicant(s)/Patent Under Reexamination CHUNG, YUAN-FEN	
	Examiner Naeem Haq	Art Unit 3625	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0004749	01-2002	Froseth et al.	705/16
*	B	US-6,801,228	10-2004	Kargman, James B.	715/837
*	C	US-2005/0126500	06-2005	Burghardi et al.	119/051.01
*	D	US-2004/0098209	05-2004	Burghardi et al.	702/032
*	E	US-2002/0120402	08-2002	Burghardi et al.	702/19
*	F	US-6,863,023	03-2005	Burghardi et al.	119/51.02
*	G	US-6,681,717	01-2004	Burghardi et al.	119/51.02
*	H	US-5,859,414	01-1999	Grimes et al.	235/383
*	I	US-2002/0167686	11-2002	Shively et al.	358/3.29
*	J	US-2005/0055181	03-2005	Verdura et al.	703/001
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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